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Wide Temperature Range Version 4M High Speed SRAM (256-kword × 16-bit)



ADE-203-1305B (Z)

Rev. 2.0 Dec. 5, 2002

Description

The HM6216255HCI Series is a 4-Mbit high speed static RAM organized 256-k word \times 16-bit. It has realized high speed access time by employing CMOS process (6-transistor memory cell) and high speed circuit designing technology. It is most appropriate for the application which requires high speed, high density memory and wide bit width configuration, such as cache and buffer memory in system. It is packaged in 400-mil 44-pin plastic SOJ and 400-mil 44-pin plastic TSOPII.

Features

• Single 5.0 V supply: $5.0 \text{ V} \pm 10\%$

• Access time: 12 ns (max)

• Completely static memory

No clock or timing strobe required

Equal access and cycle times

Directly TTL compatible

— All inputs and outputs

• Operating current: 160 mA (max)

• TTL standby current: 40 mA (max)

CMOS standby current: 5 mA (max)

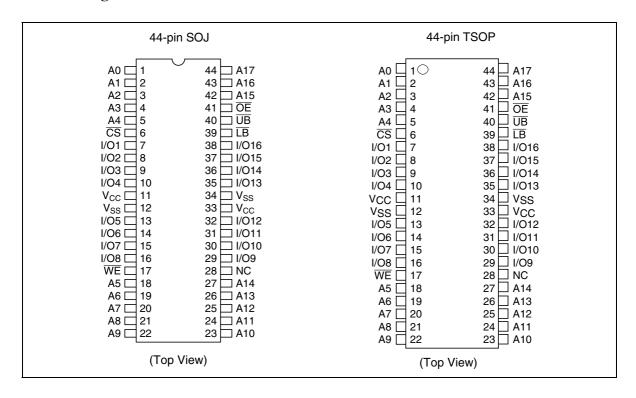
• Center V_{CC} and V_{ss} type pin out

• Temperature range: -40 to +85°C

Ordering Information

Type No.	Access time	Device marking	Package
HM6216255HCJPI-12	12 ns	HM6216255CJPI12	400-mil 44-pin plastic SOJ (CP-44D)
HM6216255HCTTI-12	12 ns	HM6216255CTTI12	400-mil 44-pin plastic TSOPII (TTP-44DE)

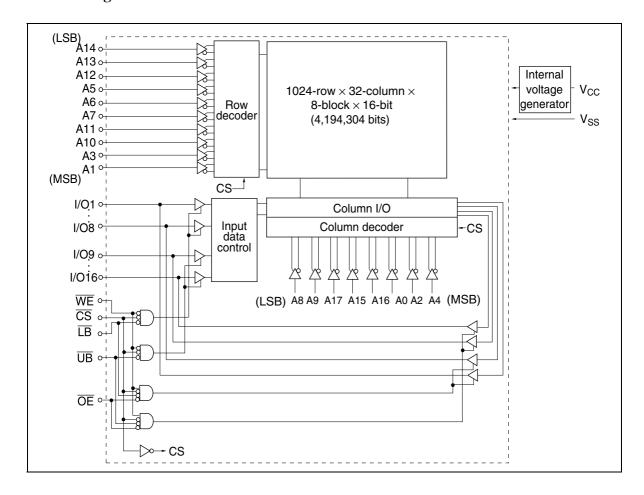
Pin Arrangement



Pin Description

Pin name	Function	
A0 to A17	Address input	
I/O1 to I/O16	Data input/output	_
CS	Chip select	
ŌĒ	Output enable	
WE	Write enable	_
UB	Upper byte select	
LB	Lower byte select	
V_{cc}	Power supply	
V_{ss}	Ground	
NC	No connection	

Block Diagram



Operation Table

CS	ŌĒ	$\overline{\text{WE}}$	<u>LΒ</u>	UB	Mode	\mathbf{V}_{cc} current	I/O1-I/O8	I/O9–I/O16	Ref. cycle
Н	×	×	×	×	Standby	I _{SB} , I _{SB1}	High-Z	High-Z	_
L	Н	Н	×	×	Output disable	I _{cc}	High-Z	High-Z	_
L	L	Н	L	L	Read	I _{cc}	Output	Output	Read cycle
L	L	Н	L	Н	Lower byte read	I _{cc}	Output	High-Z	Read cycle
L	L	Н	Н	L	Upper byte read	I _{cc}	High-Z	Output	Read cycle
L	L	Н	Н	Н	_	I _{cc}	High-Z	High-Z	_
L	×	L	L	L	Write	I _{cc}	Input	Input	Write cycle
L	×	L	L	Н	Lower byte write	I _{cc}	Input	High-Z	Write cycle
L	×	L	Н	L	Upper byte write	I _{cc}	High-Z	Input	Write cycle
L	×	L	Н	Н	_	I _{cc}	High-Z	High-Z	_

Note: H: V_{IH} , L: V_{IL} , \times : V_{IH} or V_{IL}

Absolute Maximum Ratings

Parameter	Symbol	Value	Unit	
Supply voltage relative to V _{ss}	V _{cc}	-0.5 to +7.0	V	
Voltage on any pin relative to V _{ss}	V _T	-0.5^{*1} to $V_{cc} + 0.5^{*2}$	V	
Power dissipation	P _T	1.0	W	
Operating temperature	Topr	-40 to +85	°C	
Storage temperature	Tstg	-55 to +125	°C	
Storage temperature under bias	Tbias	-40 to +85	°C	

Notes: 1. V_T (min) = -2.0 V for pulse width (under shoot) \leq 6 ns.

2. V_T (max) = V_{CC} + 2.0 V for pulse width (over shoot) \leq 6 ns.

Recommended DC Operating Conditions

 $(Ta = -40 \text{ to } +85^{\circ}C)$

Parameter	Symbol	Min	Тур	Max	Unit	
Supply voltage	V _{cc} *3	4.5	5.0	5.5	V	
	V _{SS} * ⁴	0	0	0	V	
Input voltage	V _{IH}	2.2	_	V _{cc} + 0.5	5* ² V	
	V _{IL}	-0.5* ¹	_	0.8	V	

Notes: 1. V_{IL} (min) = -2.0 V for pulse width (under shoot) \leq 6 ns.

- 2. V_{IH} (max) = V_{CC} + 2.0 V for pulse width (over shoot) \leq 6 ns.
- 3. The supply voltage with all $\ensuremath{V_{\text{\tiny CC}}}$ pins must be on the same level.
- 4. The supply voltage with all $V_{\rm ss}$ pins must be on the same level.

DC Characteristics

 $(Ta = -40 \text{ to } +85^{\circ}\text{C}, V_{CC} = 5.0 \text{ V} \pm 10\%, V_{SS} = 0 \text{ V})$

Parameter	Symbol	Min	Typ* ¹	Max	Unit	Test conditions
Input leakage current	I _{LI}	_	_	2	μΑ	$V_{IN} = V_{SS}$ to V_{CC}
Output leakage current*1	I _{LO}	_	_	2	μΑ	$V_{IN} = V_{SS}$ to V_{CC}
Operating power supply current	I _{cc}	_	_	160	mA	$\overline{\text{CS}} = \text{V}_{\text{IL}}, \text{I}_{\text{OUT}} = \text{0 mA}$ Other inputs = $\text{V}_{\text{IH}}/\text{V}_{\text{IL}}$
Standby power supply current	I _{SB}	_	_	40	mA	$\overline{\text{CS}} = \text{V}_{\text{IH}},$ Other inputs = $\text{V}_{\text{IH}}/\text{V}_{\text{IL}}$
	I _{SB1}	_	2.5	5	mA	$V_{cc} \ge \overline{CS} \ge V_{cc} - 0.2 V$,
						(1) $0 \text{ V} \le V_{IN} \le 0.2 \text{ V} \text{ or}$
						(2) $V_{\text{CC}} \ge V_{\text{IN}} \ge V_{\text{CC}} - 0.2 \text{ V}$
Output voltage	V _{oL}	_	_	0.4	V	I _{OL} = 8 mA
	V _{OH}	2.4	_	_	V	$I_{OH} = -4 \text{ mA}$

Note: 1. Typical values are at $V_{cc} = 5.0 \text{ V}$, $Ta = +25^{\circ}\text{C}$ and not guaranteed.

Capacitance

 $(Ta = +25^{\circ}C, f = 1.0 \text{ MHz})$

Parameter	Symbol	Min	Тур	Max	Unit	Test conditions
Input capacitance*1	C _{IN}	_	_	6	pF	V _{IN} = 0 V
Input/output capacitance*1	C _{I/O}	_	_	8	pF	V _{I/O} = 0 V

Note: 1. This parameter is sampled and not 100% tested.

AC Characteristics

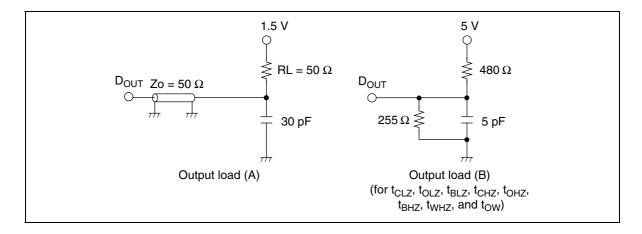
(Ta = -40 to +85°C, V_{cc} = 5.0 V \pm 10%, unless otherwise noted.)

Test Conditions

Input pulse levels: 3.0 V/0.0 VInput rise and fall time: 3 ns

• Input and output timing reference levels: 1.5 V

• Output load: See figures (Including scope and jig)



Read Cycle

HM6216255HCI

-12

Parameter	Symbol	Min	Max	Unit	Notes
Read cycle time	t _{RC}	12	_	ns	
Address access time	t _{AA}	_	12	ns	
Chip select access time	t _{ACS}	_	12	ns	
Output enable to output valid	t _{oe}	_	6	ns	
Byte select to output valid	t _{BA}	_	6	ns	
Output hold from address change	t _{oh}	3	_	ns	
Chip select to output in low-Z	t _{cLZ}	3	_	ns	1
Output enable to output in low-Z	t _{oLZ}	0	_	ns	1
Byte select to output in low-Z	t _{BLZ}	0	_	ns	1
Chip deselect to output in high-Z	t _{cHZ}	_	6	ns	1
Output disable to output in high-Z	t _{ohz}	_	6	ns	1
Byte deselect to output in high-Z	t _{BHZ}	_	6	ns	1

Write Cycle

	201	COEFLICE
піч	02 I	6255HCI

-12

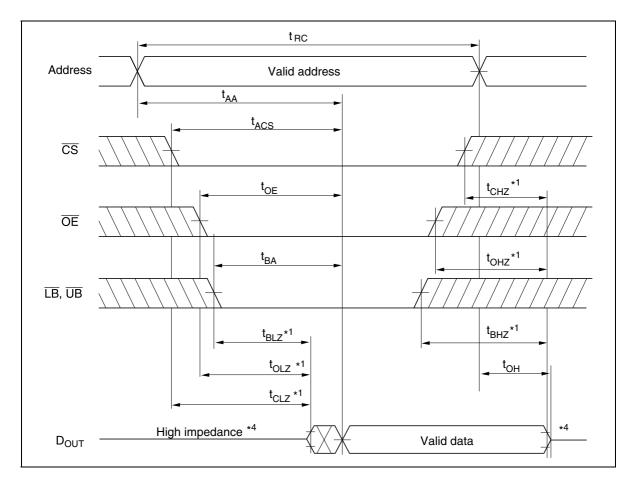
Parameter	Symbol	Min	Max	Unit	Notes
Write cycle time	t _{wc}	12	_	ns	
Address valid to end of write	t _{AW}	8	_	ns	
Chip select to end of write	t _{cw}	8	_	ns	8
Write pulse width	t _{wP}	8	_	ns	7
Byte select to end of write	t _{BW}	8	_	ns	
Address setup time	t _{AS}	0	_	ns	5
Write recovery time	t _{wr}	0	_	ns	6
Data to write time overlap	t _{DW}	6	_	ns	
Data hold from write time	t _{DH}	0	_	ns	
Write disable to output in low-Z	t _{ow}	3	_	ns	1
Output disable to output in high-Z	t _{ohz}	_	6	ns	1
Write enable to output in high-Z	t _{wHZ}		6	ns	1

Notes: 1. Transition is measured ±200 mV from steady voltage with output load (B). This parameter is sampled and not 100% tested.

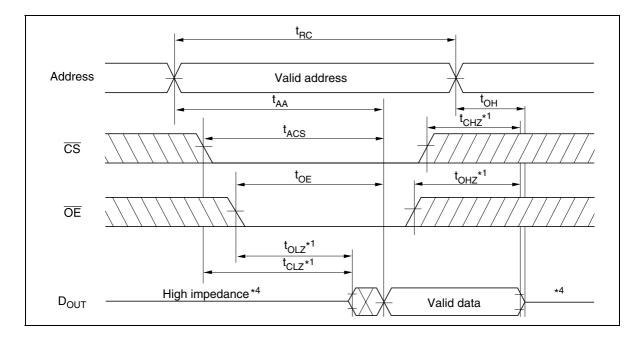
- 2. If the $\overline{\text{CS}}$ or $\overline{\text{LB}}$ or $\overline{\text{UB}}$ low transition occurs simultaneously with the $\overline{\text{WE}}$ low transition or after the $\overline{\text{WE}}$ transition, output remains a high impedance state.
- 3. WE and/or CS must be high during address transition time.
- 4. If \overline{CS} , \overline{OE} , \overline{LB} and \overline{UB} are low during this period, I/O pins are in the output state. Then the data input signals of opposite phase to the outputs must not be applied to them.
- 5. t_{AS} is measured from the latest address transition to the latest of \overline{CS} , \overline{WE} , \overline{LB} or \overline{UB} going low.
- 6. t_{WB} is measured from the earliest of \overline{CS} , \overline{WE} , \overline{LB} or \overline{UB} going high to the first address transition.
- 7. A write occurs during the overlap of a low \(\overlap{\overlap}{\overlap}\), a low \(\overlap{\overlap}{\overlap}\) and a low \(\overlap{\overlap}{\overlap}\) or a low \(\overlap{\overlap}{\overlap}\). A write begins at the latest transition among \(\overlap{\overlap}{\overlap}\) going low, \(\overlap{\overlap}{\overlap}\) going low and \(\overlap{\overlap}{\overlap}\) going low or \(\overlap{\overlap}{\overlap}\) going low, \(\overlap{\overlap}\) \(\overlap{\overlap}\) going high, \(\overlap{\overlap}\) going high, \(\overlap{\overlap}\) \(\overlap{\overlap}\) going high.
- 8. t_{cw} is measured from the later of \overline{CS} going low to the end of write.

Timing Waveforms

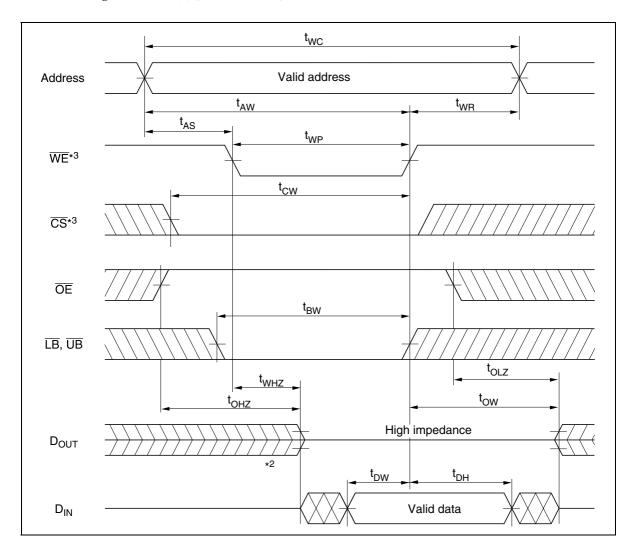
Read Timing Waveform (1) $(\overline{WE} = V_{_{IH}})$



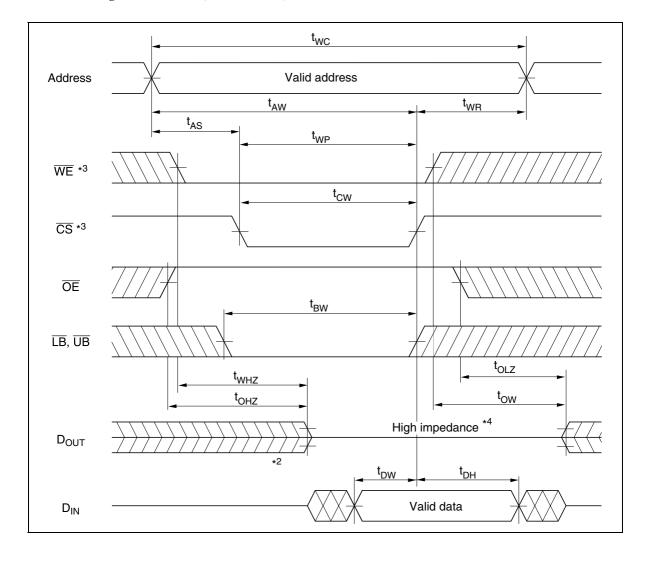
Read Timing Waveform (2) $(\overline{WE}=V_{_{IH}},\overline{LB}=V_{_{IL}},\overline{UB}=V_{_{IL}})$



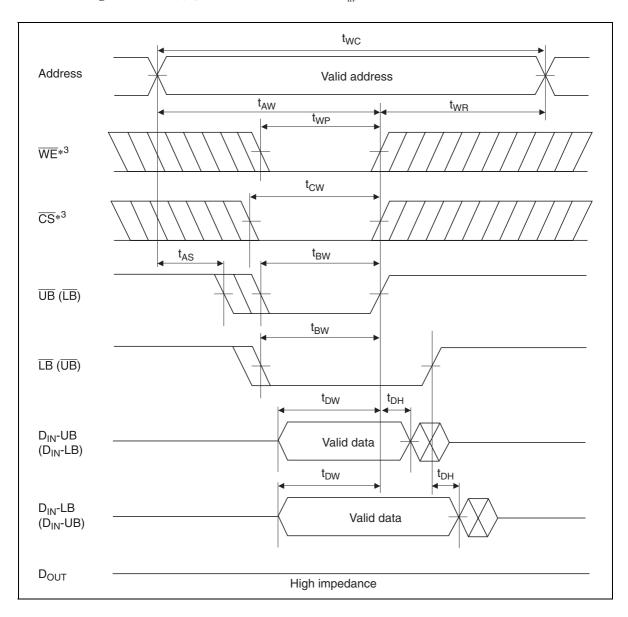
Write Timing Waveform (1) ($\overline{\text{WE}}$ Controlled)



Write Timing Waveform (2) ($\overline{\text{CS}}$ Controlled)

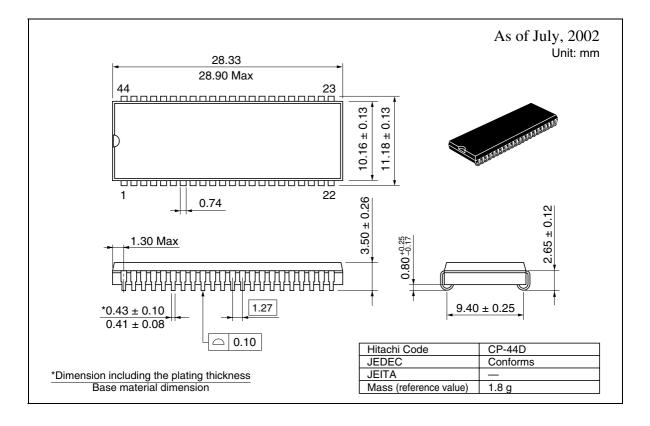


Write Timing Waveform (3) (\overline{LB} , \overline{UB} Controlled, $\overline{OE} = V_{H}$)

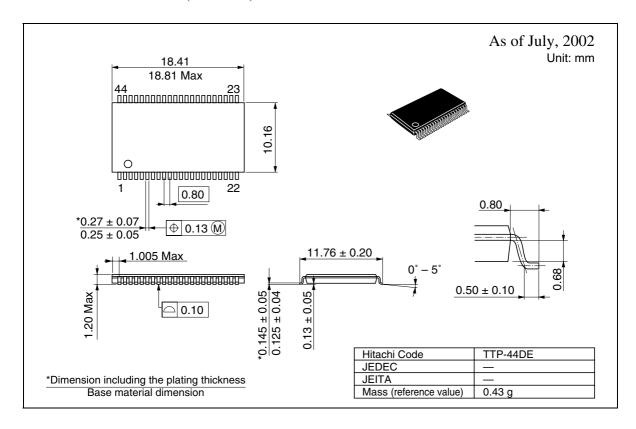


Package Dimensions

HM6216255HCJPI Series (CP-44D)



HM6216255HCTTI Series (TTP-44DE)



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TACH

Semiconductor & Integrated Circuits Nippon Bldg., 2-6-2, Öhte-machi, Chiyoda-ku, Tokyo 100-0004, Japan Tel: (03) 3270-2111 Fax: (03) 3270-5109

Hitachi Europe Ltd.

URL http://www.hitachisemiconductor.com/

For further information write to:

Hitachi Semiconductor (America) Inc. 179 East Tasman Drive San Jose, CA 95134 Tel: <1> (408) 433-1990 Maidenhead

Electronic Components Group Whitebrook Park Lower Cookham Road Fax: <1>(408) 433-0223 Berkshire SL6 8YA, United Kingdom Fax: <65>-6538-6933/6538-3877 Tel: <44> (1628) 585000 Fax: <44> (1628) 778322

> Hitachi Europe GmbH Electronic Components Group Dornacher Str 3 D-85622 Feldkirchen Postfach 201, D-85619 Feldkirchen Germany Tel: <49> (89) 9 9180-0 Fax: <49> (89) 9 29 30 00

Hitachi Asia Ltd. Hitachi Tower 16 Collyer Quay #20-00 Singapore 049318 Tel: <65>-6538-6533/6538-8577

URL: http://semiconductor.hitachi.com.sg Tel: <852>-2735-9218

Hitachi Asia Ltd. (Taipei Branch Office) 4/F, No. 167, Tun Hwa North Road Hung-Kuo Building Taipei (105), Taiwan Tel: <886>-(2)-2718-3666 Fax: <886>-(2)-2718-8180 Telex: 23222 HAS-TP

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Hitachi Asia (Hong Kong) Ltd. Group III (Electronic Components) 7/F., North Tower

World Finance Centre Harbour City, Canton Road

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